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// INNOVATION
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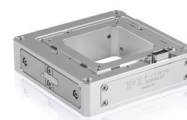
Manual Stage
25x25mm Travel



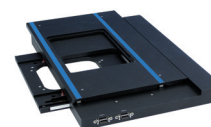
High-Speed Nanofocus
<1nm Resolution



XYZ Flexure Stage
<1nm Resolution



UHV Piezo Stage
0.1nm Resolution, XYZ



XY Piezo Motor
Stage, 100mm

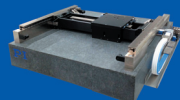
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Vacuum Stages



Piezo Mechanics



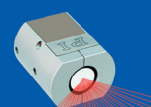
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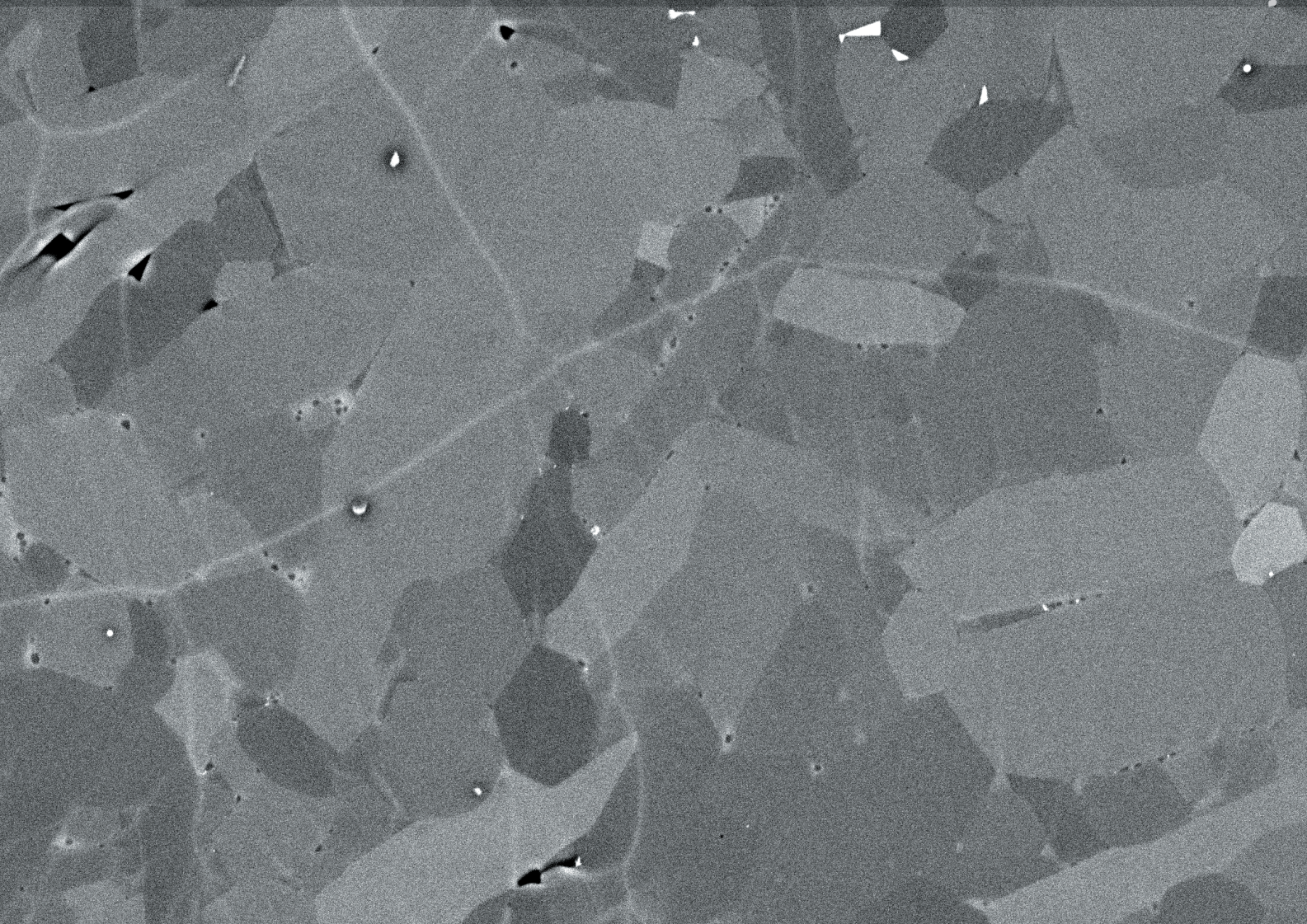
Support Performance Value

DV-502

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- High vacuum gate valve for rapid cycling
- Recipe development

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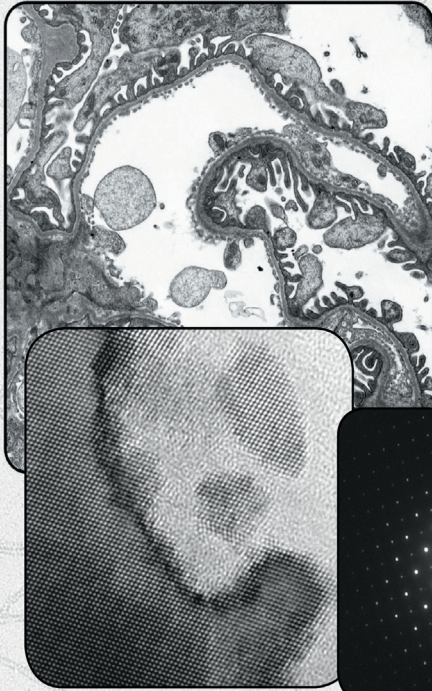
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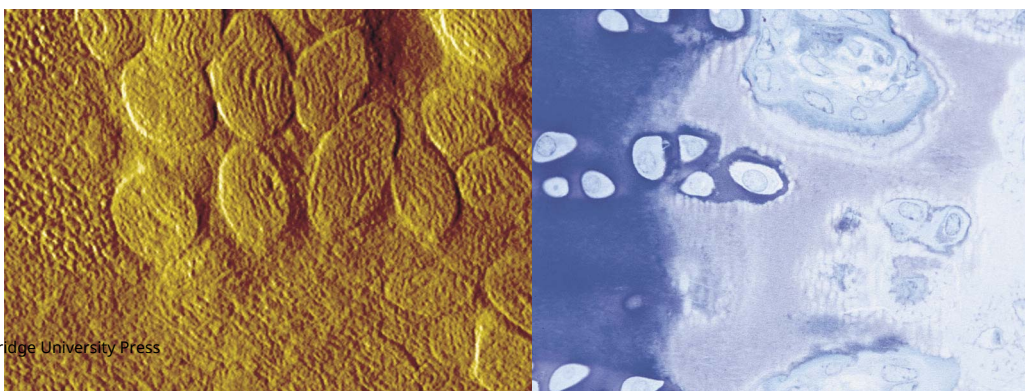
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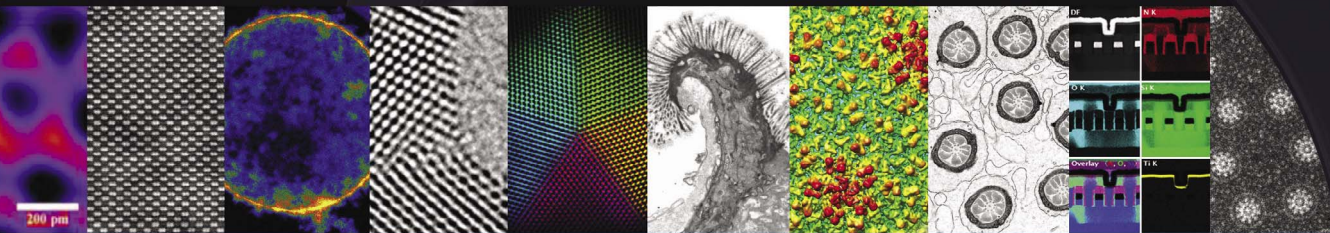
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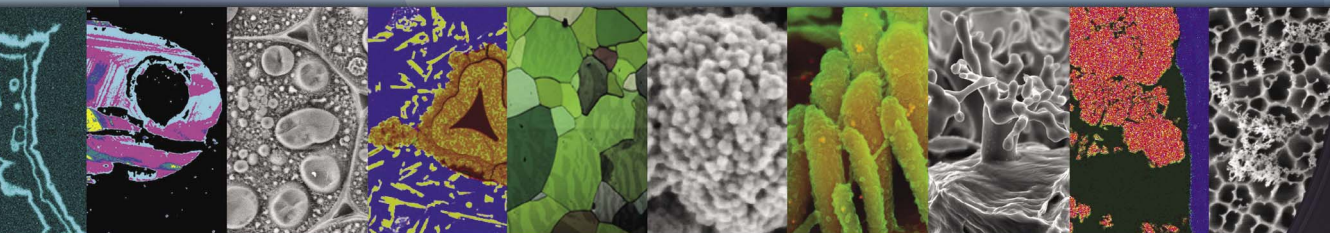


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